

May 1988 Revised August 1999

## 74F373

## **Octal Transparent Latch with 3-STATE Outputs**

#### **General Description**

The 74F373 consists of eight latches with 3-STATE outputs for bus organized system applications. The flip-flops appear transparent to the data when Latch Enable (LE) is HIGH. When LE is LOW, the data that meets the setup times is latched. Data appears on the bus when the Output Enable ( $\overline{\text{OE}}$ ) is LOW. When  $\overline{\text{OE}}$  is HIGH the bus output is in the high impedance state.

#### **Features**

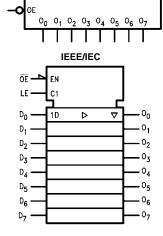
- Eight latches in a single package
- 3-STATE outputs for bus interfacing
- Guaranteed 4000V minimum ESD protection

### **Ordering Code:**

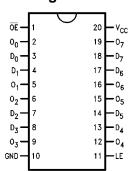
Order Number	Package Number	Package Description
74F373SC	M20B	20-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-013, 0.300 Wide
74F373SJ	M20D	20-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide
74F373MSA	MSA20	20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide
74F373PC	N20A	20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

## **Logic Symbols**



### **Connection Diagram**



## **Unit Loading/Fan Out**

Pin Names	Description	U.L. HIGH/LOW	Input I <sub>IH</sub> /I <sub>IL</sub> Output I <sub>OH</sub> /I <sub>OL</sub>		
D <sub>0</sub> –D <sub>7</sub>	Data Inputs	1.0/1.0	20 μA/-0.6 mA		
LE	Latch Enable Input (Active HIGH)	1.0/1.0	20 μA/-0.6 mA		
ŌĒ	Output Enable Input (Active LOW)	1.0/1.0	20 μA/-0.6 mA		
O <sub>0</sub> -O <sub>7</sub>	3-STATE Latch Outputs	150/40 (33.3)	-3 mA/24 mA (20 mA)		

#### **Functional Description**

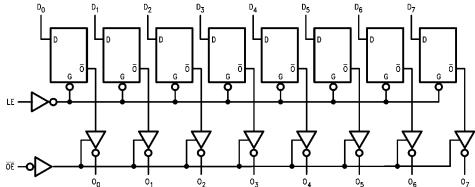
The 74F373 contains eight D-type latches with 3-STATE output buffers. When the Latch Enable (LE) input is HIGH, data on the  $D_n$  inputs enters the latches. In this condition the latches are transparent, i.e., a latch output will change state each time its D input changes. When LE is LOW, the latches store the information that was present on the D inputs a setup time preceding the HIGH-to-LOW transition of LE. The 3-STATE buffers are controlled by the Output Enable  $(\overline{OE})$  input. When  $\overline{OE}$  is LOW, the buffers are in the bi-state mode. When  $\overline{OE}$  is HIGH the buffers are in the high impedance mode but this does not interfere with entering new data into the latches.

#### **Truth Table**

	Inputs	Output			
LE	OE	D <sub>n</sub>	O <sub>n</sub>		
Н	L	Н	Н		
Н	L	L	L		
L	L	Χ	O <sub>n</sub> (no change)		
Х	Н	Х	Z		

H = HIGH Voltage Level L = LOW Voltage Level

## **Logic Diagram**



Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

X = Immaterial

Z = High Impedance State

## **Absolute Maximum Ratings**(Note 1)

<sub>150°C</sub> Conditions

 $\begin{array}{ll} \mbox{Storage Temperature} & -65^{\circ}\mbox{C to } +150^{\circ}\mbox{C} \\ \mbox{Ambient Temperature under Bias} & -55^{\circ}\mbox{C to } +125^{\circ}\mbox{C} \\ \end{array}$ 

Input Current (Note 2)

-30 mA to +5.0 mA

Voltage Applied to Output in HIGH State (with V<sub>CC</sub> = 0V)

 $\begin{array}{lll} \mbox{Standard Output} & -0.5\mbox{V to V}_{\mbox{CC}} \\ \mbox{3-STATE Output} & -0.5\mbox{V to } +5.5\mbox{V} \end{array}$ 

Current Applied to Output

in LOW State (Max)  ${\rm twice\ the\ rated\ I_{OL}\ (mA)}$  ESD Last Passing Voltage (Min)  ${\rm 4000V}$ 

Free Air Ambient Temperature  $0^{\circ}\text{C} \text{ to } +70^{\circ}\text{C}$  Supply Voltage +4.5V to +5.5V

**Recommended Operating** 

**Note 1:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

#### **DC Electrical Characteristics**

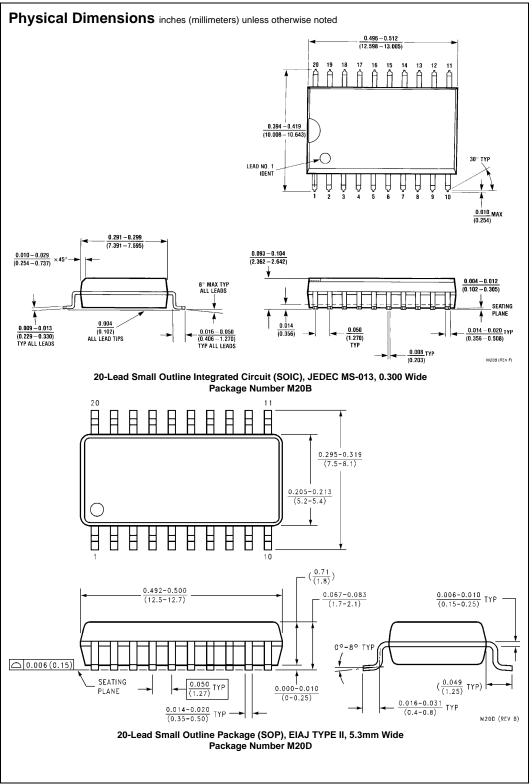
Symbol	Parameter		Min	Тур	Max	Units	v <sub>cc</sub>	Conditions
V <sub>IH</sub>	Input HIGH Voltage		2.0			V		Recognized as a HIGH Signal
V <sub>IL</sub>	Input LOW Voltage				0.8	V		Recognized as a LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage				-1.2	V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH	10% V <sub>CC</sub>	2.5					I <sub>OH</sub> = -1 mA
	Voltage	10% V <sub>CC</sub>	2.4			V	Min	$I_{OH} = -3 \text{ mA}$
		5% V <sub>CC</sub>	2.7			V	IVIII	$I_{OH} = -1 \text{ mA}$
		5% V <sub>CC</sub>	2.7					$I_{OH} = -3 \text{ mA}$
V <sub>OL</sub>	Output LOW	10% V <sub>CC</sub>			0.5	V	Min	I <sub>OL</sub> = 24 mA
	Voltage							
I <sub>IH</sub>	Input HIGH				5.0	μA	Max	V <sub>IN</sub> = 2.7V
	Current				5.0	μА	IVIAX	v <sub>IN</sub> = 2.7 v
I <sub>BVI</sub>	Input HIGH Current				7.0		Max	V <sub>IN</sub> = 7.0V
	Breakdown Test				7.0	μА	IVIAX	$v_{IN} = 7.0v$
I <sub>CEX</sub>	Output HIGH				50		Max V	V <sub>OLIT</sub> = V <sub>CC</sub>
	Leakage Current				50	μА	IVIAX	VOUT = VCC
V <sub>ID</sub>	Input Leakage		4.75			V	0.0	$I_{ID} = 1.9  \mu A$
	Test		4.73			V	0.0	All Other Pins Grounded
I <sub>OD</sub>	Output Leakage				3.75		0.0	V <sub>IOD</sub> = 150 mV
	Circuit Current				3.75	μА	0.0	All Other Pins Grounded
I <sub>IL</sub>	Input LOW Current				-0.6	mA	Max	V <sub>IN</sub> = 0.5V
l <sub>OZH</sub>	Output Leakage Current				50	μΑ	Max	V <sub>OUT</sub> = 2.7V
l <sub>OZL</sub>	Output Leakage Current				-50	μΑ	Max	V <sub>OUT</sub> = 0.5V
los	Output Short-Circuit Current		-60		-150	mA	Max	V <sub>OUT</sub> = 0V
I <sub>ZZ</sub>	Bus Drainage Test				500	μΑ	0.0V	V <sub>OUT</sub> = 5.25V
I <sub>CCZ</sub>	Power Supply Current			38	55	mA	Max	V <sub>O</sub> = HIGH Z

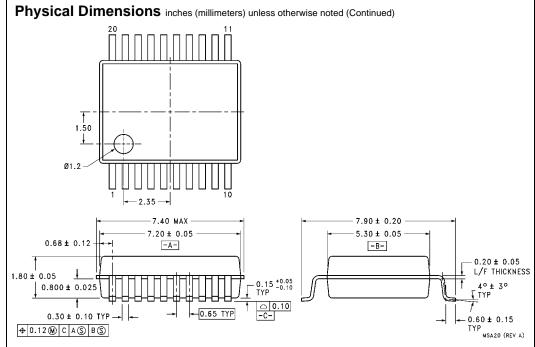
## **AC Electrical Characteristics**

Symbol	Parameter	$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$			$T_{A} = -55^{\circ}C \text{ to } +125^{\circ}C$ $V_{CC} = +5.0V$ $C_{L} = 50 \text{ pF}$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$ $C_L = 50$ pF		Units
		Min	Тур	Max	Min	Max	Min	Max	
t <sub>PLH</sub>	Propagation Delay	3.0	5.3	7.0	3.0	8.5	3.0	8.0	
t <sub>PHL</sub>	D <sub>n</sub> to O <sub>n</sub>	2.0	3.7	5.0	2.0	7.0	2.0	6.0	ns
t <sub>PLH</sub>	Propagation Delay	5.0	9.0	11.5	5.0	15.0	5.0	13.0	
t <sub>PHL</sub>	LE to O <sub>n</sub>	3.0	5.2	7.0	3.0	8.5	3.0	8.0	ns
t <sub>PZH</sub>	Output Enable Time	2.0	5.0	11.0	2.0	13.5	2.0	12.0	
t <sub>PZL</sub>		2.0	5.6	7.5	2.0	10.0	2.0	8.5	ns
t <sub>PHZ</sub>	Output Disable Time	1.5	4.5	6.5	1.5	10.0	1.5	7.5	ns
t <sub>PLZ</sub>		1.5	3.8	5.0	1.5	7.0	1.5	6.0	115

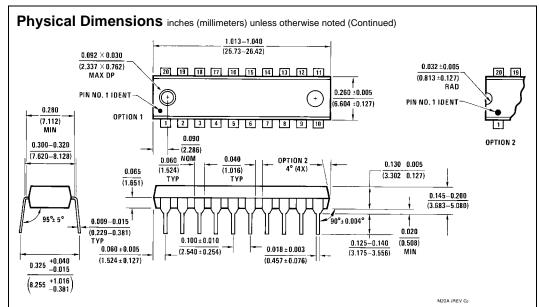
# **AC Operating Requirements**

		$T_A = +25$ °C $V_{CC} = +5.0V$		$T_A = -55$ °C to +125°C $V_{CC} = +5.0V$		$T_A = 0$ °C to +70°C $V_{CC} = +5.0V$		Units
Symbol	Parameter							
		Min	Max	Min	Max	Min	Max	
t <sub>S</sub> (H)	Setup Time, HIGH or LOW	2.0		2.0		2.0		
t <sub>S</sub> (L)	D <sub>n</sub> to LE	2.0		2.0		2.0		ns
t <sub>H</sub> (H)	Hold Time, HIGH or LOW	3.0		3.0		3.0		115
t <sub>H</sub> (L)	D <sub>n</sub> to LE	3.0		4.0		3.0		
t <sub>W</sub> (H)	LE Pulse Width, HIGH	6.0		6.0		6.0		ns





20-Lead Shrink Small Outline Package (SSOP), EIAJ TYPE II, 5.3mm Wide Package Number MSA20



20-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide Package Number N20A

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